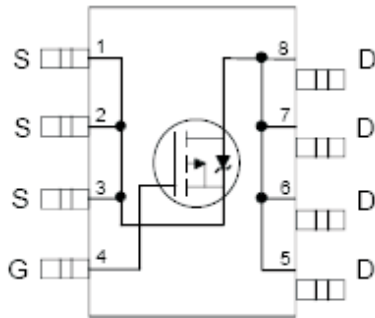
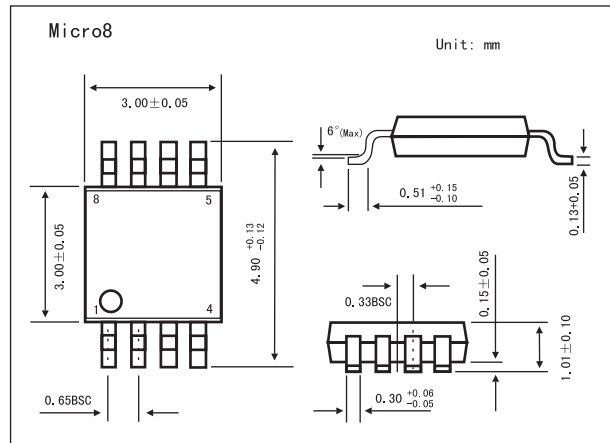


# HEXFET<sup>®</sup> Power MOSFET

## KRF7606

### ■ Features

- Generation V Technology
- Ultra Low On-Resistance
- P-Channel MOSFET
- Very Small SOIC Package
- Low Profile (<1.1mm)
- Available in Tape & Reel
- Fast Switching



### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	-30	V
Continuous Drain Current, $V_{GS} @ -10V @ T_a = 25^\circ\text{C}$	$I_D$	-3.6	A
Continuous Drain Current, $V_{GS} @ -10V @ T_a = 70^\circ\text{C}$	$I_D$	-2.9	
Pulsed Drain Current *1	$I_{DM}$	-29	
Power Dissipation @ $T_a = 25^\circ\text{C}$	$P_D$	1.8	W
Power Dissipation @ $T_a = 70^\circ\text{C}$		1.1	
Linear Derating Factor		14	
Gate-to-Source Voltage	$V_{GS}$	$\pm 20$	V
Gate-to-Source Voltage Single Pulse $t_p < 10 \mu\text{s}$	$V_{GSM}$	30	V
Peak Diode Recovery $dv/dt$ *2	$dv/dt$	-5.0	$\text{V/ns}$
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to + 150	$^\circ\text{C}$
Maximum Junction-to-Ambient *3	$R_{\theta JA}$	70	$^\circ\text{C/W}$


\*1 Repetitive rating; pulse width limited by max. junction temperature.

\*2  $I_{SD} \leq -2.4\text{A}$ ,  $di/dt \leq -130\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 150^\circ\text{C}$

\*3 Surface mounted on FR-4 board,  $t \leq 10\text{sec}$ .

## KRF7606

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250 \mu A$	-30			V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(BR)DSS}/\Delta T_J$	$I_D = -1mA, \text{Reference to } 25^\circ C$		-0.024		V/°C
Static Drain-to-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = -10V, I_D = -2.4A^{*1}$		0.075	0.09	mΩ
		$V_{GS} = -4.5V, I_D = -1.2A^{*1}$		0.130	0.15	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250 \mu A$	-1.0			V
Forward Transconductance	$g_{fs}$	$V_{DS} = -10V, I_D = -1.2A^{*1}$	2.3			S
Drain-to-Source Leakage Current	$I_{DSS}$	$V_{DS} = -24V, V_{GS} = 0V$			-1.0	μA
		$V_{DS} = -24V, V_{GS} = 0V, T_J = 125^\circ C$			-25	
Gate-to-Source Forward Leakage	$I_{GSS}$	$V_{GS} = -20V$			-100	nA
Gate-to-Source Reverse Leakage		$V_{GS} = 20V$			100	
Total Gate Charge	$Q_g$	$I_D = -2.4A$		20	30	nC
Gate-to-Source Charge	$Q_{gs}$	$V_{DS} = -24V$		2.1	3.1	
Gate-to-Drain ("Miller") Charge	$Q_{gd}$	$V_{GS} = -10V$		7.6	11	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -10V$		13		ns
Rise Time	$t_r$	$I_D = -2.4A$		20		
Turn-Off Delay Time	$t_{d(off)}$	$R_G = 6 \Omega$		43		
Fall Time	$t_f$	$R_D = 4.0 \Omega$		39		
Input Capacitance	$C_{iss}$	$V_{GS} = 0V$		520		pF
Output Capacitance	$C_{oss}$	$V_{DS} = -25V$		300		
Reverse Transfer Capacitance	$C_{rss}$	$f = 1.0MHz$		140		
Continuous Source Current (Body Diode)	$I_S$	MOSFET symbol showing the integral reverse p-n junction diode. 			-1.8	A
Pulsed Source Current (Body Diode) *2	$I_{SM}$				-29	
Diode Forward Voltage	$V_{SD}$	$T_J = 25^\circ C, I_S = -2.4A, V_{GS} = 0V^{*1}$			-1.2	V
Reverse Recovery Time	$t_{rr}$	$T_J = 25^\circ C, I_F = -2.4A$		43	64	ns
Reverse Recovery Charge	$Q_{rr}$	$di/dt = -100A/\mu s^{*1}$		50	76	μC

\*1 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .

\*2 Repetitive rating; pulse width limited by max. junction temperature.